IN THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

1. (Original) An aberration measuring method in which a light flux converged by a condensing optical system is made incident on an optical system to be measured, the light flux that has passed through said optical system to be measured is reflected by a reflecting optical system having a center of curvature at a light convergence point on a light emergence side of said optical system to be measured is made incident on said optical system to be measure again, and wavefront aberration of said optical system to be measured is detected as interference fringes using the light flux that has passed through said optical system to be measured again, comprising:

   a step of setting a numerical aperture of said optical system to be measured to a numerical aperture larger than a maximum numerical aperture in a case that said optical system is actually used; and

   a step of measuring wavefront aberration of said optical system at a set numerical aperture.

2. (Original) An aberration measuring method according to claim 1, wherein letting NA_0 be said maximum numerical aperture in the case that said optical system to be measured is actually used and letting NA_1 be said set numerical aperture, the following condition is satisfied:

   $NA_0/NA_1 < 0.995$.

3-5. (Cancelled)